

MOS-FET DIODE

di/dt TESTER di/dtテスター  
**GST610Z**

600V  
100A



MOS-FET DIODE

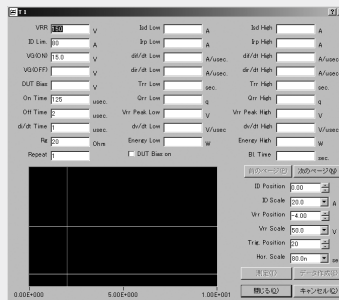
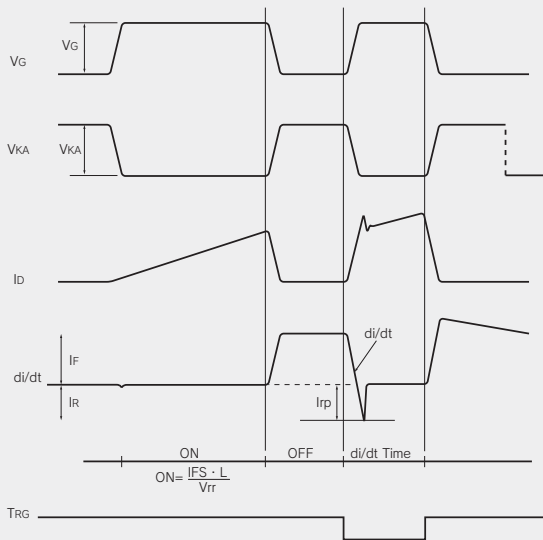
di/dt TESTER di/dtテスター  
**GSTM410Z**

400V  
100A



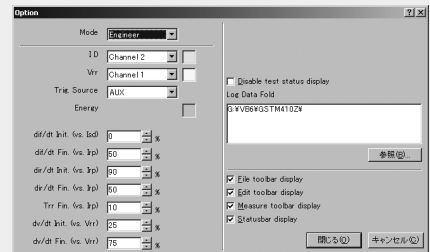
- GST610Z & GSTM410Z has been designed to seek and judge di/dt characteristic with software by using reverse recovery waveform of MOS-FETs and diodes or break waveform with digital oscilloscope. It has OPEN/SHORT test and driver check functions to improve reliability.
- MOS-FETやダイオードの逆回復波形や破壊波形をオシロスコープから取り込み、ソフトウェアでdi/dtを求めその特性を判定します。OPEN/SHORT試験、ドライバーチェック機能もあり信頼性を向上させています。

Reference Waveform

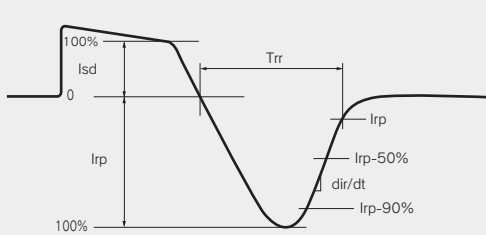


Software Display

Measurement Point Setting

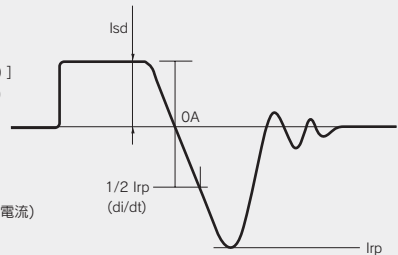


Reference Waveform (di/dt measurement regulation [di/dt測定規定])



di/dt [ Ird · (95%~0%) ⇔ Irp · (0%~95%) ]  
Fall(立下り) Fall(立下り)  
Trr [ 0~Irp · (95%~0%) ]  
Rise(立上り)  
dir/dt [ Irp · 90% ⇔ Irp · 50% ]  
Rise(立上り) Rise(立上り)

Ird : Diode forward current(ダイオードの順方向電流)  
Irp : Irr peak current(Irrのピーク電流)



MODEL	GST610Z	GSTM410Z
Vrr VOLTAGE	30V~599V	30V~400V
GATE VOLTAGE	ON +0V~+39.9V OFF -0V~-39.9V	ON +0V~+39.9V OFF -0V~-39.9V
D.U.T. BIAS	00.0V~+15.0V 00.0V~-15.0V	00.0V~+39.9V 00.0V~-39.9V
GATE PULSE	ON 2.0μs~999.9μs OFF 1μs~999μs	ON 1μs~999μs OFF 1μs~999μs
di/dt TIME	1μs~999μs	1μs~999μs
Rg	0.1Ω~99.9Ω	1Ω~999Ω
Id LIMIT	0.1A~99.9A	0A~99A
PRE/POST CHECK	OPEN(Vsd(Vf) > 3V) SHORT(Vdss(Vr) < Vrr Setting × 80%)	OPEN(Vsd(Vf) > 3V) SHORT(Vdss(Vr) < Vrr Setting × 80%)
DRIVER CHECK	OPEN(Vds(SAT) > Vrr Setting × 20%) SHORT(Vdss < Vrr Setting × 80%)	OPEN(Vds(SAT) > Vrr Setting × 20%) SHORT(Vdss < Vrr Setting × 80%)
DIMENSIONS & WEIGHT		
MAIN UNIT	430(W) × 550(D) × 245(H) ... 34kg	430(W) × 700(D) × 245(H) ... 42kg
HEAD BOX	150(W) × 660(D) × 250(H) + Coil ... 22kg	250(W) × 640(D) × 224(H) + Coil ... 21kg